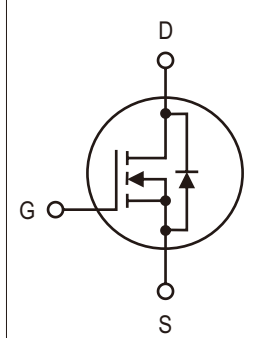


- 特点：导通电阻低 开关速度快 输入阻抗高 符合ROHS规范
- FEATURES: ■ LOW ON-RESISTANCE ■ FAST SWITCHING ■ HIGH INPUT RESISTANCE ■ ROHS COMPLIANT
- 应用：电子镇流器 电子变压器 开关电源 LED驱动器
- APPLICATION: ■ ELECTRONIC BALLAST ■ ELECTRONIC TRANSFORMER ■ SWITCH MODE POWER SUPPLY ■ LED DRIVER

● 最大额定值：(Tc=25°C)

● Absolute Maximum Ratings (Tc=25°C) TO-220/TO-220F

参数 PARAMETER	符号 SYMBOL	额定值 VALUE	单位 UNIT
漏-源电压 Drain-source Voltage	V <sub>DS</sub>	650	V
栅-源电压 Gate-source Voltage	V <sub>GS</sub>	±30	V
漏极电流 Continuous Drain Current Tc=25°C	I <sub>D</sub>	20.0*	A
漏极电流 Continuous Drain Current Tc=100°C	I <sub>D</sub>	14.0*	A
最大脉冲电流 Drain Current-Pulsed ①	I <sub>DM</sub>	80*	A
耗散功率 Power Dissipation	P <sub>D</sub>	150	W
最高结温 Junction Temperature	T <sub>J</sub>	120	°C
存储温度 Storage Temperature	T <sub>STG</sub>	-55-150	°C
单脉冲雪崩能量 Single Pulse Avalanche Energy ②	EAS	363	mJ

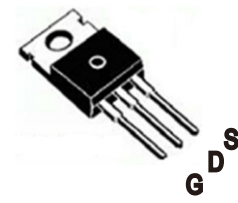


V<sub>DS</sub>=650V

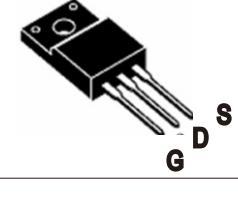
R<sub>DS(ON)</sub>=0.40Ω

I<sub>D</sub>=20.0A

TO-220



TO-220F



\*漏极电流由最高结温限制

\*Drain current limited by maximum junction temperature

- 热特性
- Thermal Characteristics

参数 PARAMETER	符号 SYMBOL	最小值 MIN	典型值 TYP	最大值 MAX	单位 UNIT
热阻结-壳 Thermal Resistance Junction-case	R <sub>thJC</sub>			0.72/1.04	°C/W
热阻结-环境 Thermal Resistance Junction-ambient	R <sub>thJA</sub>			62.5	°C/W

- 订购信息
- Ordering Information

普通塑封料 Lead Free	产品丝印 Marking	封装外形 Package	包装形式 Packing	包装数量 packing quantity				
SI20N65F	SI20N65F	TO-220F	Tube	50Pcs/Tube	20T/Box	1.0K/Box	5B/Carton	50K/Carton
SI20N65P	SI20N65P	TO-220P	Tube	50Pcs/Tube	20T/Box	1.0K/Box	5B/Carton	50K/Carton

Note: T: Tube/管 R: Reel/卷盘 B: Box/内盒 C: Carton/箱

- 电特性：(Tc=25°C)
- Electronic Characteristics (Tc=25°C)

参数 PARAMETER	符号 SYMBOL	测试条件 TEST CONDITION	最小值 MIN	典型值 TYP	最大值 MAX	单位 UNIT	
漏-源击穿电压 Drain-source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V, I <sub>D</sub> =250μA	650			V	
击穿电压温度系数 Breakdown Voltage Temperature Coefficient	ΔBV <sub>DSS</sub> /ΔT <sub>J</sub>	I <sub>D</sub> =250μA, Referenced to 25°C		0.6		V/°C	
栅极开启电压 Gate Threshold Voltage	V <sub>GS(TH)</sub>	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250μA	3.0		4.0	V	
漏-源漏电流 Drain-source Leakage Current	I <sub>DSS</sub>	V <sub>DS</sub> =650V, V <sub>GS</sub> =0V, T <sub>J</sub> =25°C			1	μA	
		V <sub>DS</sub> =520V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C			100	μA	
栅极漏电流 Gate-body Leakage Current (V <sub>DS</sub> =0)	I <sub>GSS</sub>	V <sub>GS</sub> =±30V			±100	nA	
漏-源导通电阻 Static Drain-source On Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =10V, I <sub>D</sub> =10.0A ③		0.35	0.40	Ω	
输入电容 Input Capacitance	C <sub>iss</sub>	V <sub>GS</sub> =0V, V <sub>DS</sub> =25V, F=1.0MHz		2701		pF	
输出电容 Output Capacitance	C <sub>oss</sub>				249		pF
反相转移电容 Reverse Transfer Capacitance	C <sub>rss</sub>				25		pF
开启延迟时间 Turn-On Delay Time	T <sub>d(on)</sub>	V <sub>DD</sub> =250V, I <sub>D</sub> =20.0A R <sub>G</sub> =25Ω ③		54		ns	
上升时间 Turn-On Rise Time	T <sub>r</sub>			48		ns	
关断延迟时间 Turn-Off Delay Time	T <sub>d(off)</sub>			301		ns	
下降时间 Turn-Off Fall Time	T <sub>f</sub>			85		ns	
栅极电荷 Total Gate Charge	Q <sub>g</sub>	I <sub>D</sub> =20.0A, V <sub>DS</sub> =520V V <sub>GS</sub> =10V ③		80		nC	
栅源电荷 Gate-to-Source Charge	Q <sub>gs</sub>			12		nC	
栅漏电荷 Gate-to-Drain Charge	Q <sub>gd</sub>			34		nC	
二极管正向电流 Continuous Diode Forward Current	I <sub>s</sub>				20.0	A	
二极管正向压降 Diode Forward Voltage	V <sub>SD</sub>	T <sub>J</sub> =25°C, I <sub>s</sub> =20.0A V <sub>GS</sub> =,0V ③			1.4	V	
反向恢复时间 Reverse Recovery Time	T <sub>rr</sub>	T <sub>J</sub> =25°C, I <sub>f</sub> =20.0A di/dt=100A/μS ③		741		ns	
反向恢复电荷 Reverse Recovery Charge	Q <sub>rr</sub>				4.7		uC

注释 (Notes):

①脉冲宽度: 以最高结温为限制

Repetitive rating: Pulse width limited by maximum junction temperature

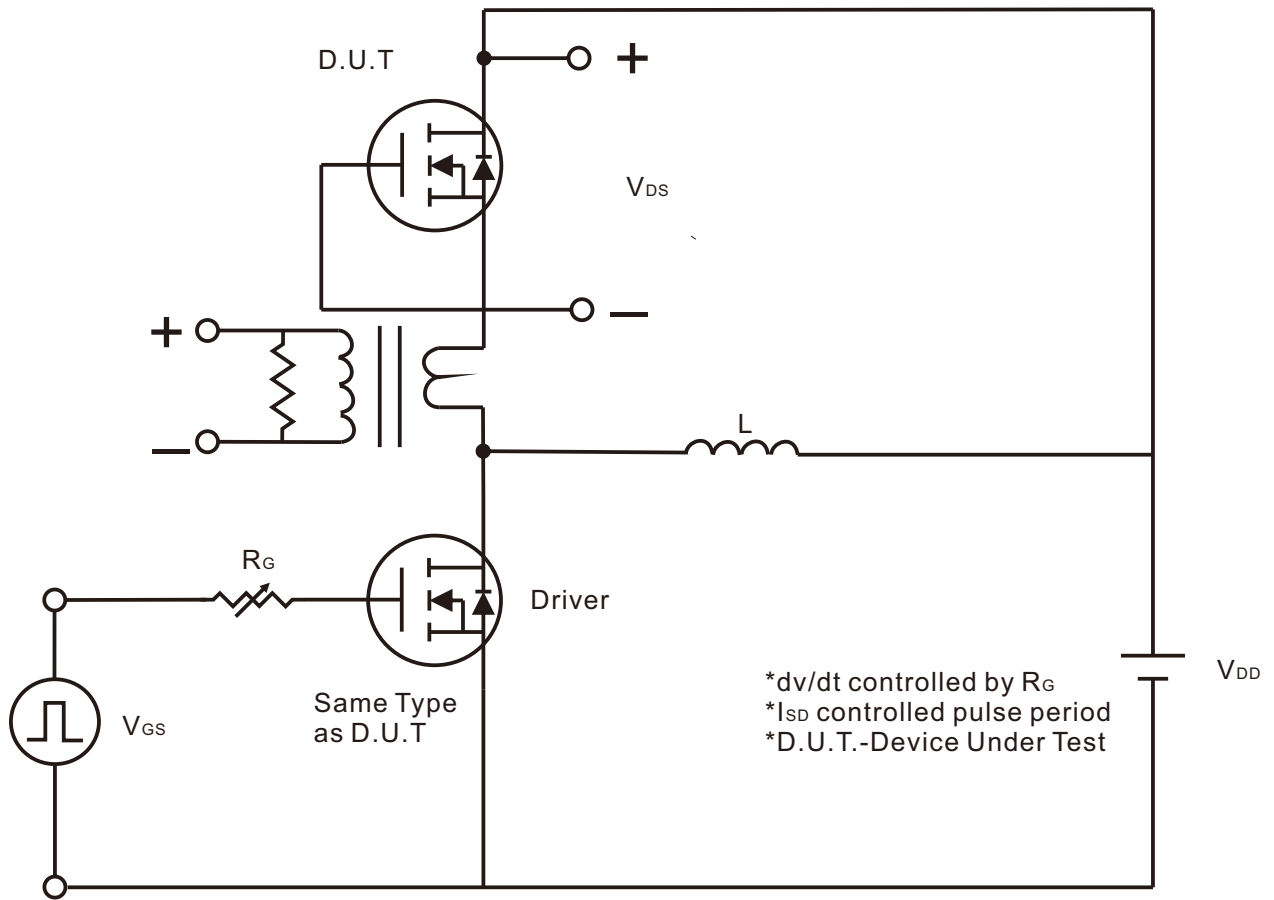
②初始结温=25°C, V<sub>DD</sub>=50V, L=10mH, R<sub>G</sub>=25Ω, I<sub>AS</sub>=15.5A

Starting T<sub>J</sub>=25°C, V<sub>DD</sub>=50V, L=10mH, R<sub>G</sub>=25Ω, I<sub>AS</sub>=15.5A

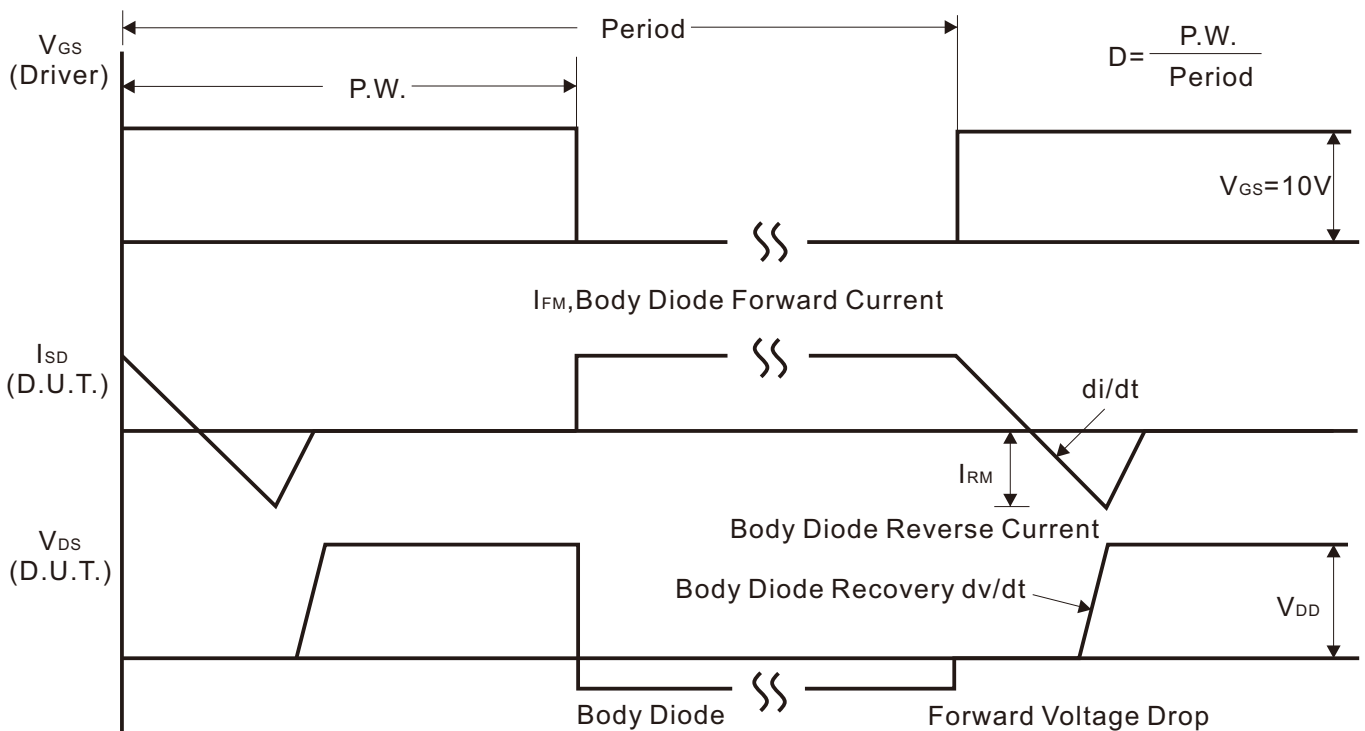
③脉冲测试: 脉冲宽度≤300μs, 占空比≤2%

Pulse Test: Pulse width≤300μs, Duty cycle≤2%

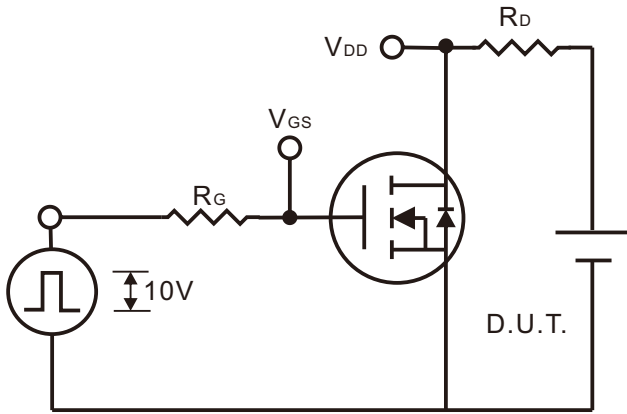
● TEST CIRCUITS AND WAVEFORMS



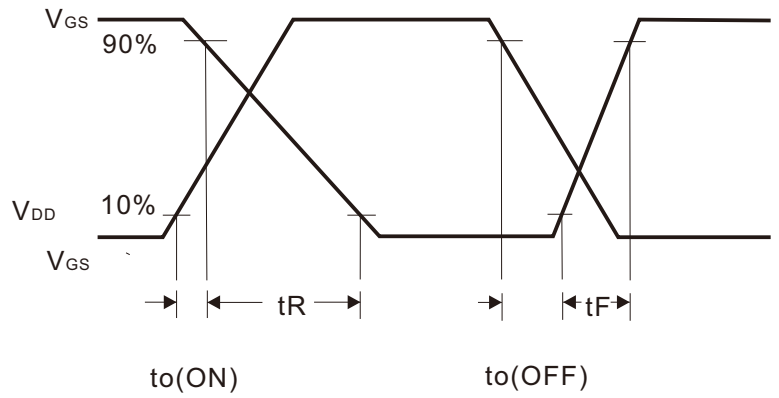
Peak Diode Recovery Test Circuit



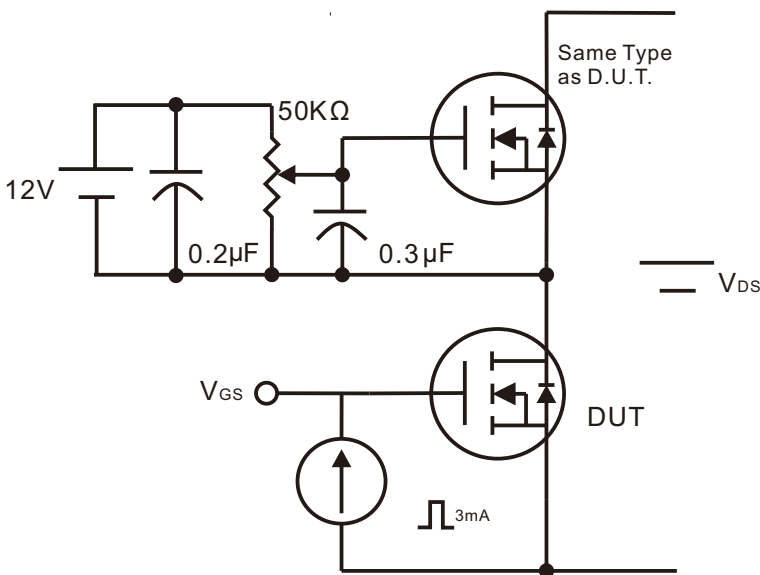
Peak Diode Recovery dv/dt Waveforms



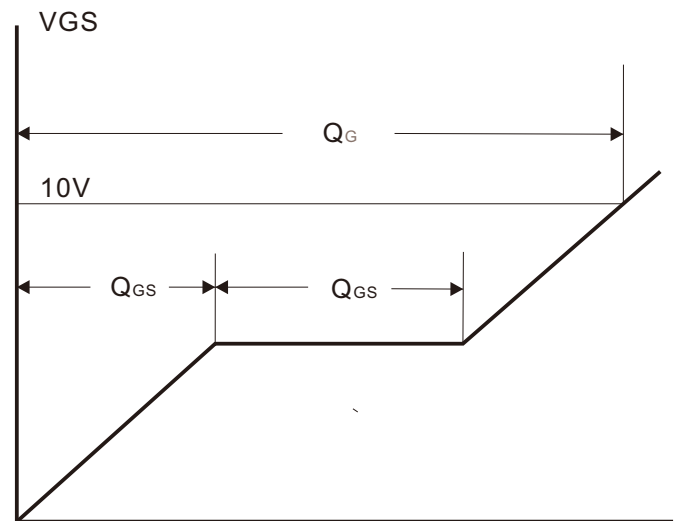
Switching Test Circuit



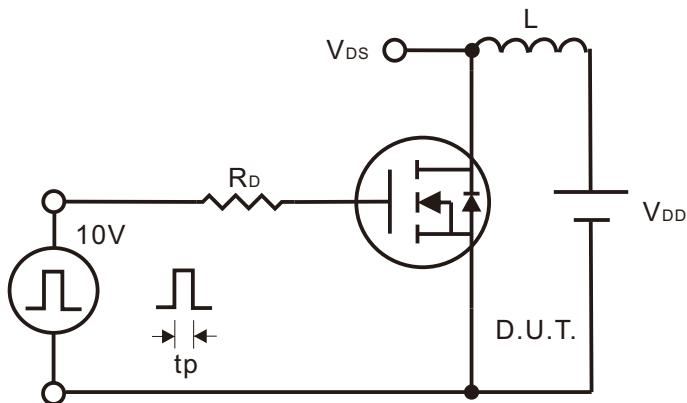
Switching Waveforms



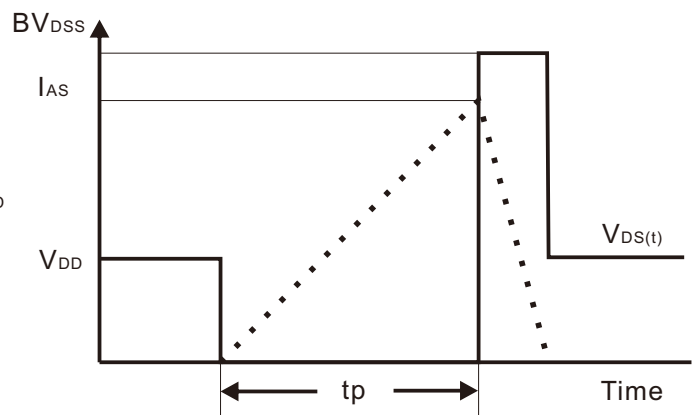
Gate Charge Test Circuit



Gate Charge Waveform



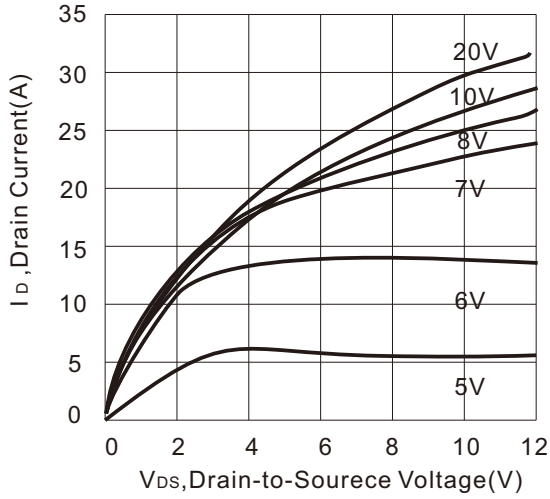
Unclamped Inductive Switching Test Circuit



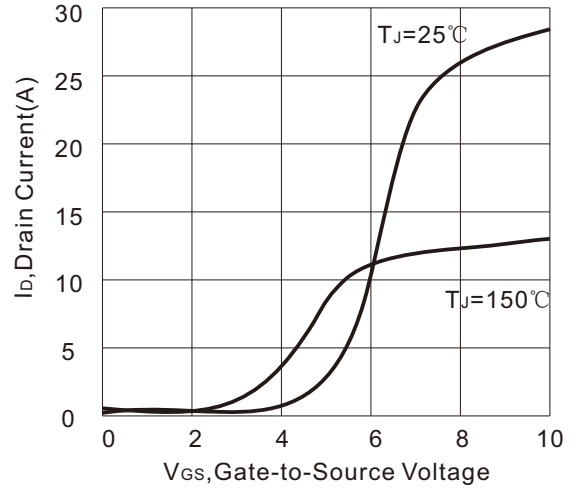
Unclamped Inductive Switching Waveforms

● 特征曲线 TYPICAL CHARACTERISTICS

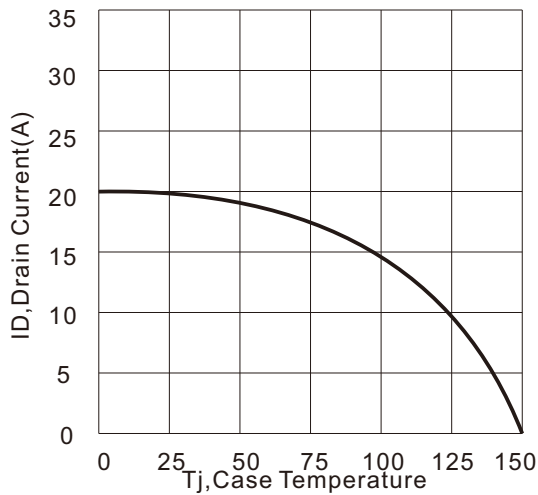
Output Characteristics



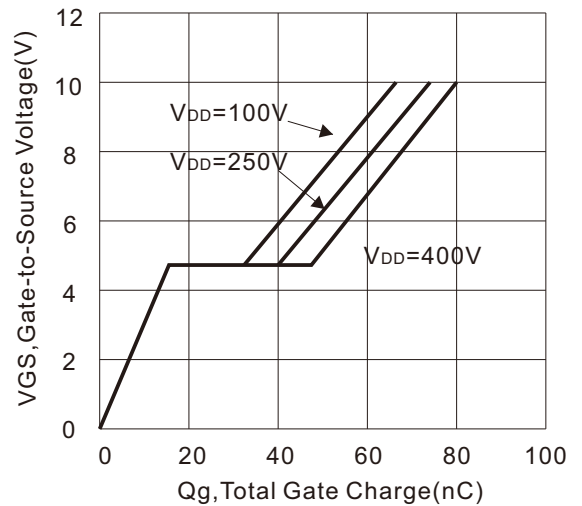
Transfer Characteristics



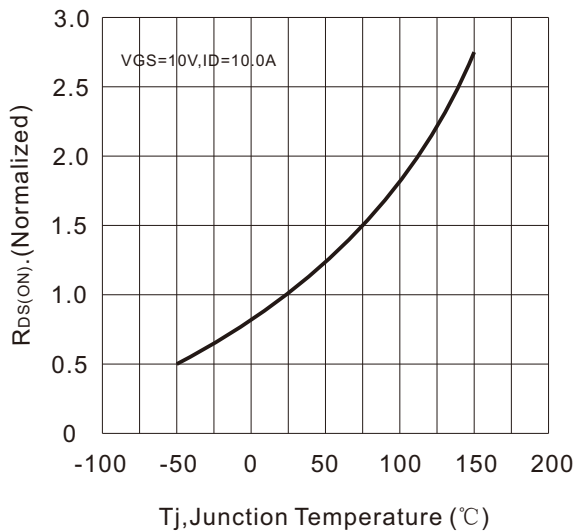
Drain Current VS. Temperature



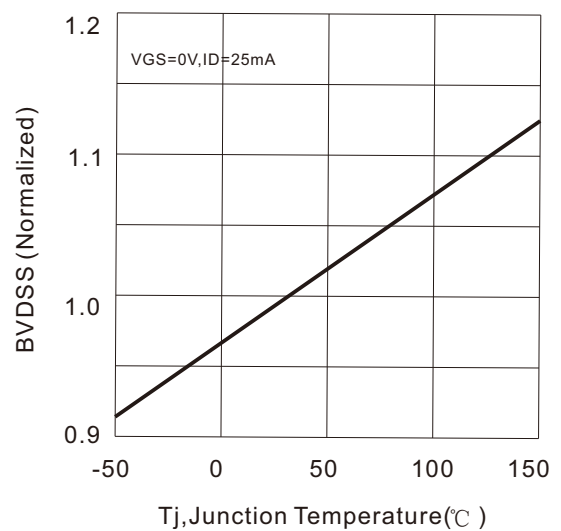
Gate Charge



On-Resistance vs. Junction Temperature



BVDS Variation VS. Temperature



● 特征曲线 TYPICAL CHARACTERISTICS

